Search History

L Number	Hits	Search Text	DB	Time stamp
-	112	(438/11).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 17:06
-	1508	(438/14).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 19:21
-	668	(438/15).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 19:21
-	450	(438/18).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 19:22
-	109	calibration with substrate and metrology	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 19:23
-	45	calibration with substrate and metrology and calibration with layer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 19:23
-	1	calibration with substrate and metrology and calibration with layer and rms	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 19:23
-	6	calibration with substrate and metrology and calibration with layer and root	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/30 06:07
-	9	calibration near layer and rms	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:04
-	4	calibration near layer same (silicon adj dioxide or halfnium adj dioxide or aluminum adj dioxide or tantalum adj dioxide or halfnium adj silicate or zicronium adj silicate or zicronium adj oxide)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/30 06:18
-	15	calibration near layer and metrology	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:04
-	1	"5851842".PN.	USPAT	2004/08/30 06:20
-	915	(438/16).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:01
-	3675	(438/17).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:01

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–	8	calibra$4 with layer and rms and metrology	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:05
–	102	calibra$4 with layer and rms	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:05
1	1628	438/778	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:11
2	1213	438/787	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/06 03:11

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